

## **Power MOSFET**

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	650				
R <sub>DS(on)</sub> (Ω)	V <sub>GS</sub> = 10 V 0.6				
Q <sub>g</sub> (Max.) (nC)	200				
Q <sub>gs</sub> (nC)	24				
Q <sub>gd</sub> (nC)	110				
Configuration	Single				

#### **FEATURES**

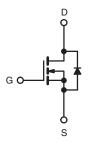
- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC





D<sup>2</sup>PAK (TO-263)





N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T <sub>C</sub> = 25 °C, unless otherwise noted)					
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage	V <sub>DS</sub>	650	V		
Gate-Source Voltage		$V_{GS}$	± 20	v	
Continuous Drain Current	$V_{GS}$ at 10 V $T_{C} = 25 ^{\circ}C$ $T_{C} = 100 ^{\circ}C$		12		
Continuous Drain Current	Ι <sub>D</sub>	9	Α		
Pulsed Drain Current <sup>a</sup>		I <sub>DM</sub>	36		
Linear Derating Factor		1.5	W/°C		
Single Pulse Avalanche Energy <sup>b</sup>	E <sub>AS</sub>	880	mJ		
Repetitive Avalanche Current <sup>a</sup>	I <sub>AR</sub>	8.7	Α		
Repetitive Avalanche Energy <sup>a</sup>	E <sub>AR</sub>	19	mJ		
Maximum Power Dissipation	$P_{D}$	190	W		
Peak Diode Recovery dV/dtc	dV/dt	1.5	V/ns		
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C		
Soldering Recommendations (Peak Temperature)	•	300 <sup>d</sup>	1		
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in	
Mounting Torque	0-32 OF IVIS SCIEW		1.1	N⋅m	

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b.  $V_{DD} = 50 \text{ V}$ , starting  $T_J = 25 \,^{\circ}\text{C}$ ,  $L = 37 \,\text{mH}$ ,  $R_g = 25 \,^{\circ}\Omega$ ,  $I_{AS} = 6.7 \,\text{A}$  (see fig. 12). c.  $I_{SD} \le 6.7 \,^{\circ}\Lambda$ ,  $I_{AS} = 6.7 \,^{\circ}\Lambda$
- d. 1.6 mm from case.

<sup>\*</sup> Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS					
PARAMETER SYMBOL TYP. MAX. U					
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	40		
Case-to-Sink, Flat, Greased Surface	R <sub>thCS</sub>	0.24	-	°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.65		

PARAMETER	SYMBOL	TEST	CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static		<u>.</u>					
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0$	V, I <sub>D</sub> = 250 μA	650	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference t	o 25 °C, I <sub>D</sub> = 1 mA	-	1.2	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V$	<sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>	V <sub>G</sub>	<sub>S</sub> = ± 20 V	-	-	± 100	nA
Zana Oata Valta aa Dusin Ouwant		V <sub>DS</sub> = 68	V <sub>DS</sub> = 650 V, V <sub>GS</sub> = 0 V		-	100	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 560 V, V	<sub>'GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	500	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 4.0 A <sup>b</sup>	-	0.6	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> = 10	00 V, I <sub>D</sub> = 4.0 A <sup>b</sup>	4.9	-	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0 V,		-	2900	-	
Output Capacitance	C <sub>oss</sub>	V	os = 25 V,	-	270	-	pF
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0 l	MHz, see fig. 5	-	92	-	
Total Gate Charge	Qg				-	200	
Gate-Source Charge	$Q_{gs}$	V <sub>GS</sub> = 10 V	$I_D = 6.7 \text{ A}, V_{DS} = 360 \text{ V},$ see fig. 6 and 13 <sup>b</sup>	-	-	24	nC
Gate-Drain Charge	Q <sub>gd</sub>	1	see lig. 6 and 13-		-	110	]
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD}$ = 475 V, $I_{D}$ = 6.7 A , $R_{G}$ = 6.2 Ω, $R_{D}$ = 67 Ω, see fig. 10 <sup>b</sup>		-	20	-	ns
Rise Time	t <sub>r</sub>			-	34	-	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	130	-	
Fall Time	t <sub>f</sub>			-	37	-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") fro	Between lead, 6 mm (0.25") from		5.0	-	-11
Internal Source Inductance	L <sub>S</sub>	package and center of die contact		-	13	-	- nH
Drain-Source Body Diode Characteristic	s				•	•	
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbo	MOSFET symbol showing the		-	9	A
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	integral reverse p - n junction diode		ı	-	1 8	
Body Diode Voltage	$V_{SD}$	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 6.7 A, V <sub>GS</sub> = 0 V <sup>b</sup>		ı	-	1.8	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	$T_{\rm J} = 25~{\rm ^{\circ}C},~I_{\rm F} = 6.7~{\rm A},~{\rm dl/dt} = 100~{\rm A/\mu s^b}$		ı	610	920	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	3.2	4.8	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> and L <sub>D</sub> )				L <sub>D</sub> )	

### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width  $\leq$  300 µs; duty cycle  $\leq$  2 %.



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

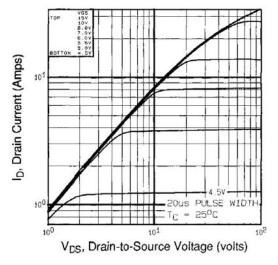


Fig. 1 - Typical Output Characteristics, T<sub>C</sub> = 25 °C

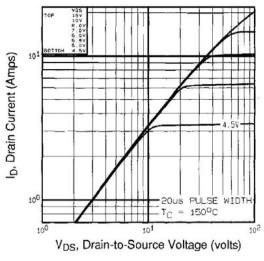


Fig. 2 - Typical Output Characteristics,  $T_C = 150$  °C

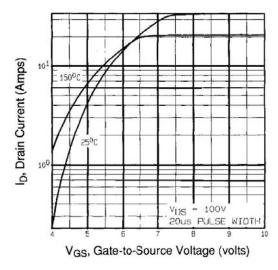


Fig. 3 - Typical Transfer Characteristics

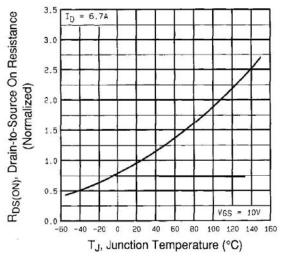


Fig. 4 - Normalized On-Resistance vs. Temperature



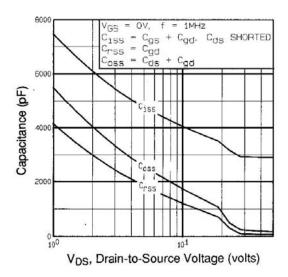


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

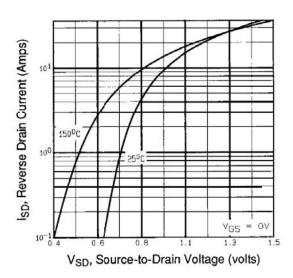


Fig. 7 - Typical Source-Drain Diode Forward Voltage

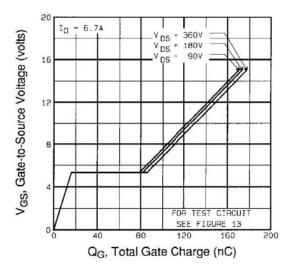


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

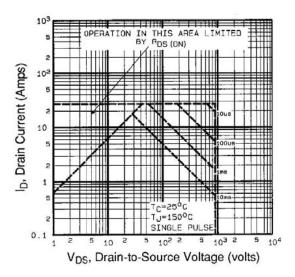


Fig. 8 - Maximum Safe Operating Area



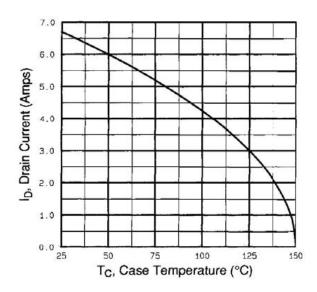


Fig. 9 - Maximum Drain Current vs. Case Temperature

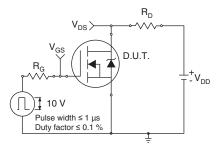


Fig. 10a - Switching Time Test Circuit

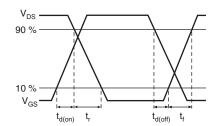


Fig. 10b - Switching Time Waveforms

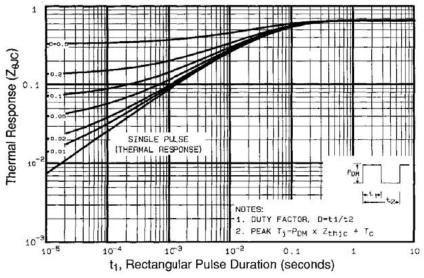


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



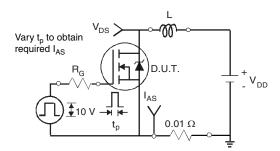


Fig. 12a - Unclamped Inductive Test Circuit

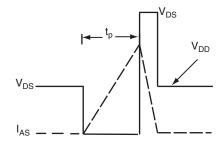


Fig. 12b - Unclamped Inductive Waveforms

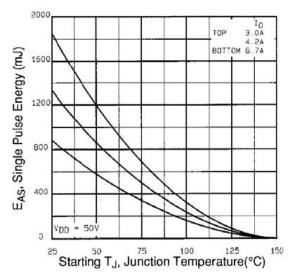


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

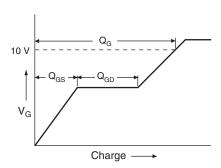


Fig. 13a - Basic Gate Charge Waveform

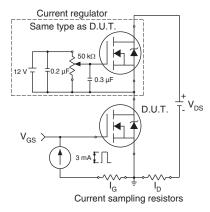
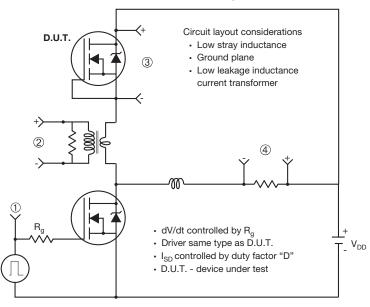


Fig. 13b - Gate Charge Test Circuit



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#### Peak Diode Recovery dV/dt Test Circuit



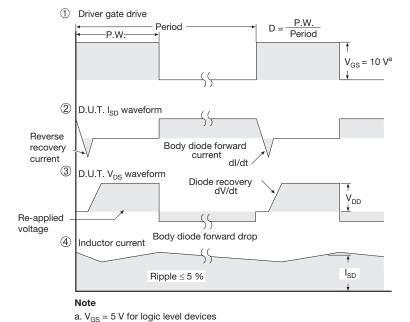
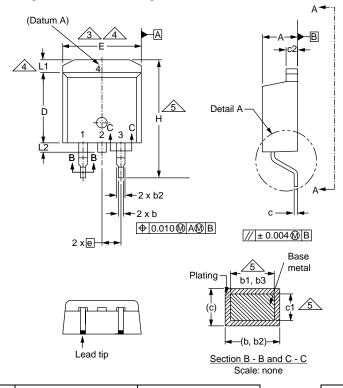
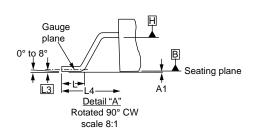


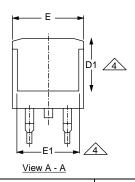
Fig. 14 - For N-Channel



### **TO-263AB (HIGH VOLTAGE)**







	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
Α	4.06	4.83	0.160	0.190
A1	0.00	0.25	0.000	0.010
b	0.51	0.99	0.020	0.039
b1	0.51	0.89	0.020	0.035
b2	1.14	1.78	0.045	0.070
b3	1.14	1.73	0.045	0.068
С	0.38	0.74	0.015	0.029
c1	0.38	0.58	0.015	0.023
c2	1.14	1.65	0.045	0.065
D	8.38	9.65	0.330	0.380

	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
D1	6.86	-	0.270	-
Е	9.65	10.67	0.380	0.420
E1	6.22	-	0.245	-
е	2.54 BSC		0.100 BSC	
Η	14.61	15.88	0.575	0.625
L	1.78	2.79	0.070	0.110
L1	-	1.65	-	0.066
L2	-	1.78	-	0.070
L3	0.25 BSC		0.010	BSC
L4	4.78	5.28	0.188	0.208

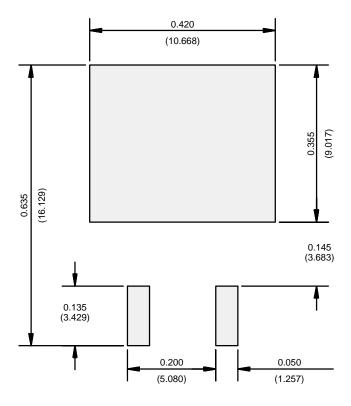
ECN: S-82110-Rev. A, 15-Sep-08 DWG: 5970

## Notes

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimensions are shown in millimeters (inches).
- 3. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm (0.005") per side. These dimensions are measured at the outmost extremes of the plastic body at datum A.
- 4. Thermal PAD contour optional within dimension E, L1, D1 and E1.
- 5. Dimension b1 and c1 apply to base metal only.
- 6. Datum A and B to be determined at datum plane H.
- 7. Outline conforms to JEDEC outline to TO-263AB.



## RECOMMENDED MINIMUM PADS FOR D<sup>2</sup>PAK: 3-Lead



Recommended Minimum Pads Dimensions in Inches/(mm)



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